

# ESD1L001, SZESD1L001

## ESD Protection Diode

### Low Capacitance ESD Protection Diode for High Speed Data Line

The ESD1L001 surge protection is designed to protect four high speed data lines from ESD. Ultra-low capacitance and low ESD clamping voltage make this device an ideal solution for protecting voltage sensitive high speed data lines. The small form factor, flow-through style package allows for easy PCB layout and matched trace lengths necessary to maintain consistent impedance between high speed differential lines such as USB 3.0 and HDMI.

#### Features

- Low Capacitance (0.3 pF Typical, I/O to GND)
- Short to Battery Survivability
- Protection for the Following IEC Standards:  
IEC 61000-4-2 Level 4 (ESD)
- Low ESD Clamping Voltage (30 V Typical, +16 A TLP, I/O to GND)
- SZ Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### Typical Applications

- USB2.0/3.0
- LVDS
- HDMI
- High Speed Differential Pairs

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

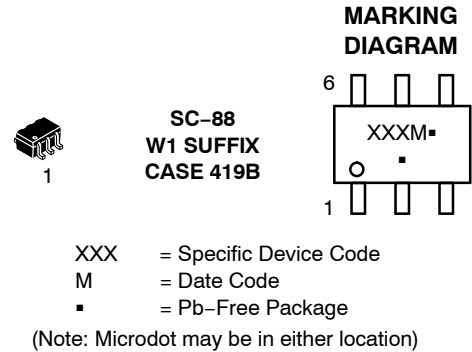
Rating	Symbol	Value	Unit
Operating Junction Temperature Range	T <sub>J</sub>	-55 to +125	°C
Storage Temperature Range	T <sub>stg</sub>	-55 to +150	°C
Lead Solder Temperature – Maximum (10 Seconds)	T <sub>L</sub>	260	°C
IEC 61000-4-2 Contact IEC 61000-4-2 Air	ESD	±8 ±15	kV kV

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

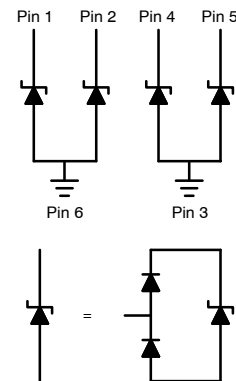


ON Semiconductor®

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#### PIN CONFIGURATION AND SCHEMATIC



#### ORDERING INFORMATION

Device	Package	Shipping
ESD1L001W1T2G	SC-88 (Pb-Free)	3000 / Tape & Reel
SZESD1L001W1T2G	SC-88 (Pb-Free)	3000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

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## ELECTRICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Reverse Working Voltage	$V_{RWM}$	I/O Pin to GND		5	16	V
Breakdown Voltage	$V_{BR}$	$I_T = 1\text{ mA}$ , I/O Pin to GND	16.5			V
Reverse Leakage Current	$I_R$	$V_{RWM} = 5\text{ V}$ , I/O Pin to GND			1	$\mu\text{A}$
Clamping Voltage (Note 1)	$V_C$	IEC61000-4-2, $\pm 8\text{ kV}$ Contact	See Figures 3 and 4			
Clamping Voltage TLP (Note 2)	$V_C$	$I_{PP} = 8\text{ A}$ $I_{PP} = 16\text{ A}$ $I_{PP} = -8\text{ A}$ $I_{PP} = -16\text{ A}$		25 30 -5.5 -10.8		V
Junction Capacitance Match	$\Delta C_J$	$V_R = 0\text{ V}$ , $f = 1\text{ MHz}$ between Pin1 to GND and Pin4 to GND		5	10	%
Junction Capacitance	$C_J$	$V_R = 0\text{ V}$ , $f = 1\text{ MHz}$ between I/O Pins		0.2	0.4	$\mu\text{F}$
Junction Capacitance	$C_J$	$V_R = 0\text{ V}$ , $f = 1\text{ MHz}$ between I/O Pins and GND		0.3	0.5	$\mu\text{F}$
3dB Bandwidth	$f_{BW}$	$R_L = 50\ \Omega$		5		GHz

- For test procedure see Figures 5 and 6 and application note AND8307/D.
- ANSI/ESD STM5.5.1 – Electrostatic Discharge Sensitivity Testing using Transmission Line Pulse (TLP) Model.  
TLP conditions:  $Z_0 = 50\ \Omega$ ,  $t_p = 100\text{ ns}$ ,  $t_r = 4\text{ ns}$ , averaging window;  $t_1 = 30\text{ ns}$  to  $t_2 = 60\text{ ns}$ .

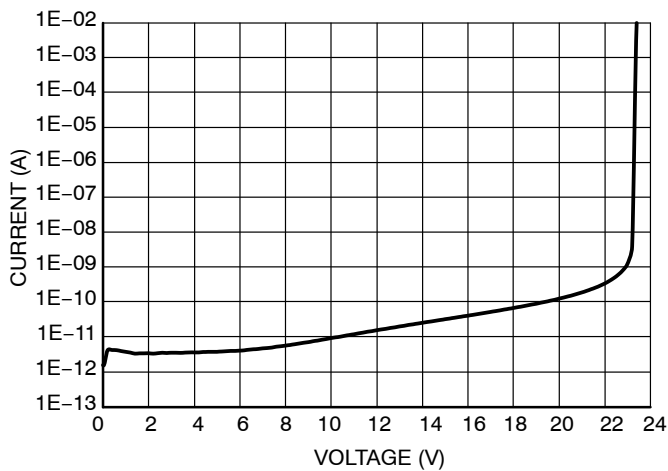


Figure 1. Typical IV Characteristic Curve

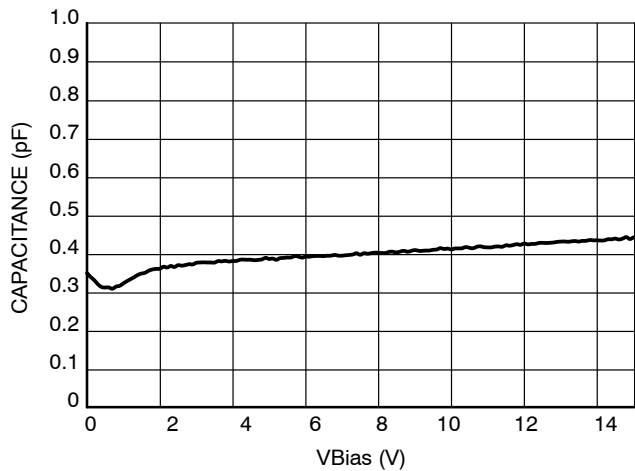


Figure 2. Typical CV Characteristic Curve

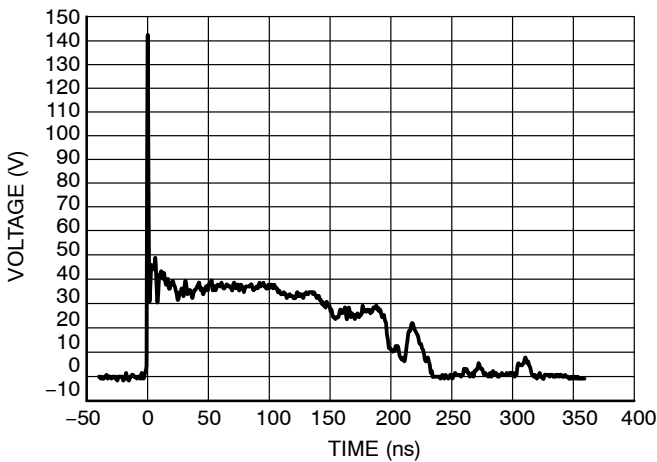


Figure 3. IEC61000-4-2 +8 kV Contact ESD Clamping Voltage

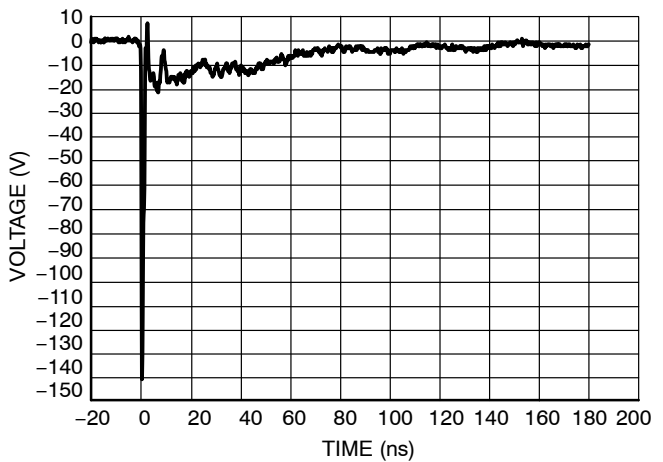


Figure 4. IEC61000-4-2 -8 kV Contact ESD Clamping Voltage

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## IEC 61000-4-2 Spec.

Level	Test Voltage (kV)	First Peak Current (A)	Current at 30 ns (A)	Current at 60 ns (A)
1	2	7.5	4	2
2	4	15	8	4
3	6	22.5	12	6
4	8	30	16	8



Figure 5. IEC61000-4-2 Spec

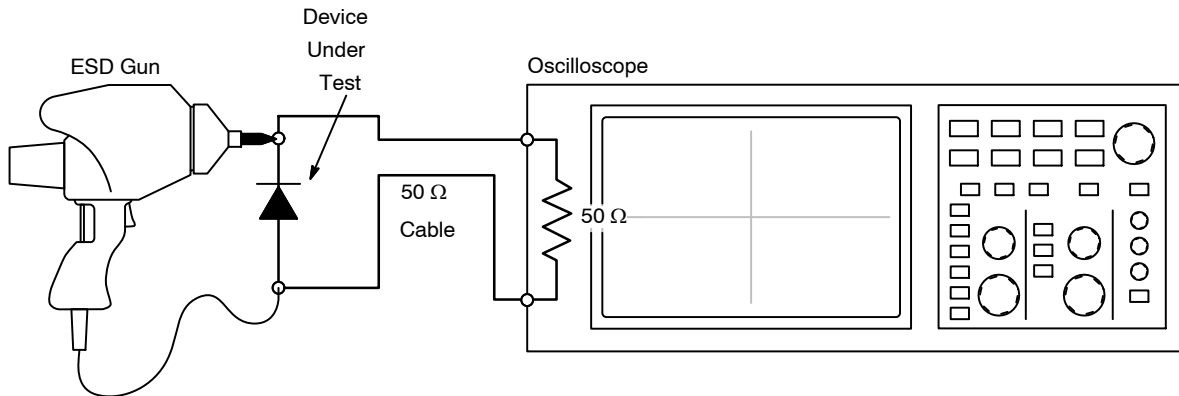


Figure 6. Diagram of ESD Clamping Voltage Test Setup

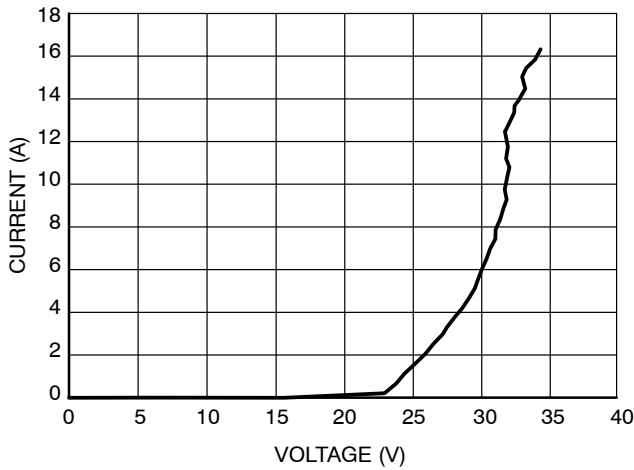
The following is taken from Application Note AND8308/D – Interpretation of Datasheet Parameters for ESD Devices.

### ESD Voltage Clamping

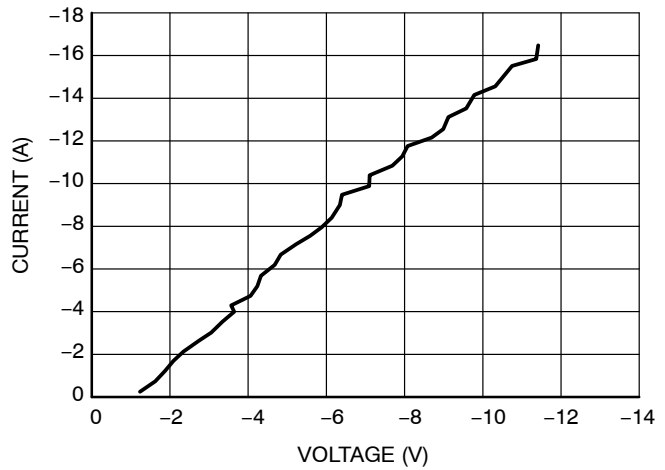
For sensitive circuit elements it is important to limit the voltage that an IC will be exposed to during an ESD event to as low a voltage as possible. The ESD clamping voltage is the voltage drop across the ESD protection diode during an ESD event per the IEC61000-4-2 waveform. Since the IEC61000-4-2 was written as a pass/fail spec for larger

systems such as cell phones or laptop computers it is not clearly defined in the spec how to specify a clamping voltage at the device level. ON Semiconductor has developed a way to examine the entire voltage waveform across the ESD protection diode over the time domain of an ESD pulse in the form of an oscilloscope screenshot, which can be found on the datasheets for all ESD protection diodes. For more information on how ON Semiconductor creates these screenshots and how to interpret them please refer to AND8307/D.

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**Figure 7. Positive TLP IV Curve**

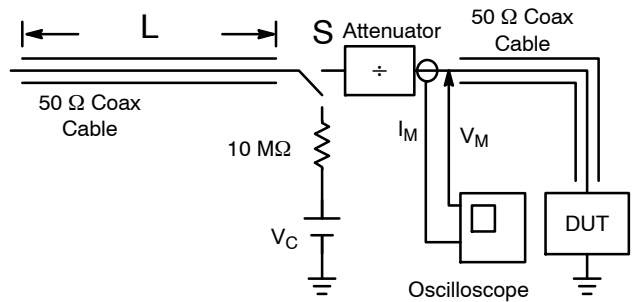


**Figure 8. Negative TLP IV Curve**

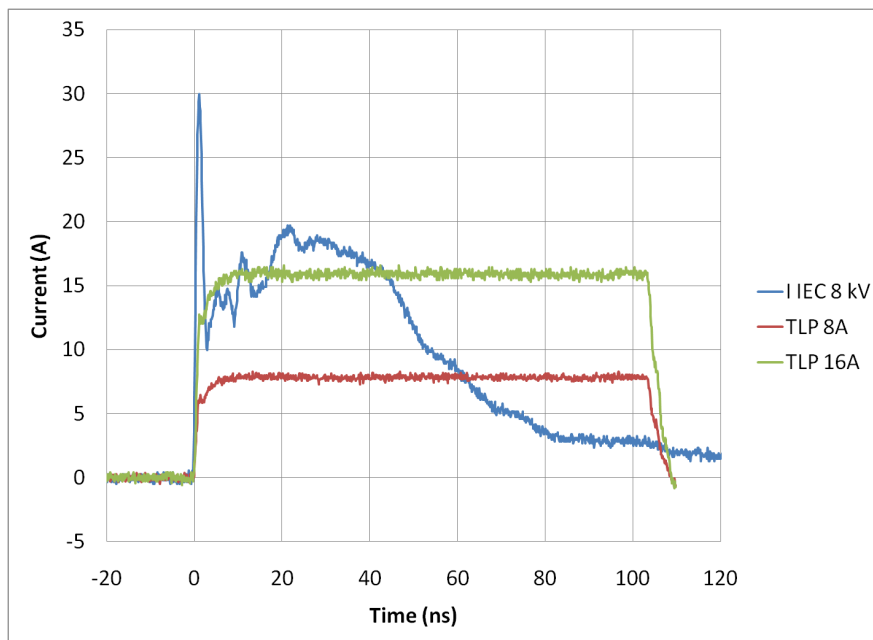
NOTE: TLP parameter:  $Z_0 = 50 \Omega$ ,  $t_p = 100 \text{ ns}$ ,  $t_r = 300 \text{ ps}$ , averaging window:  $t_1 = 30 \text{ ns}$  to  $t_2 = 60 \text{ ns}$ .

### Transmission Line Pulse (TLP) Measurement

Transmission Line Pulse (TLP) provides current versus voltage (I-V) curves in which each data point is obtained from a 100 ns long rectangular pulse from a charged transmission line. A simplified schematic of a typical TLP system is shown in Figure 9. TLP I-V curves of ESD protection devices accurately demonstrate the product's ESD capability because the 10s of amps current levels and under 100 ns time scale match those of an ESD event. This is illustrated in Figure 10 where an 8 kV IEC 61000-4-2 current waveform is compared with TLP current pulses at 8 A and 16 A. A TLP I-V curve shows the voltage at which the device turns on as well as how well the device clamps voltage over a range of current levels.



**Figure 9. Simplified Schematic of a Typical TLP System**



**Figure 10. Comparison Between 8 kV IEC 61000-4-2 and 8 A and 16 A TLP Waveforms**

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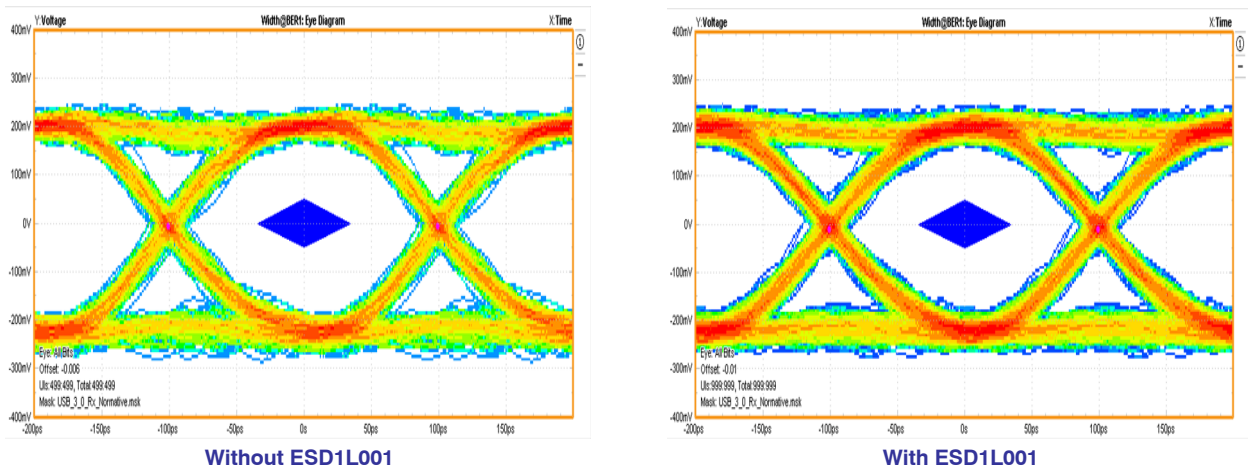


Figure 11. USB3.0 Eye Diagram with and without ESD1L001 at 5 Gb/s

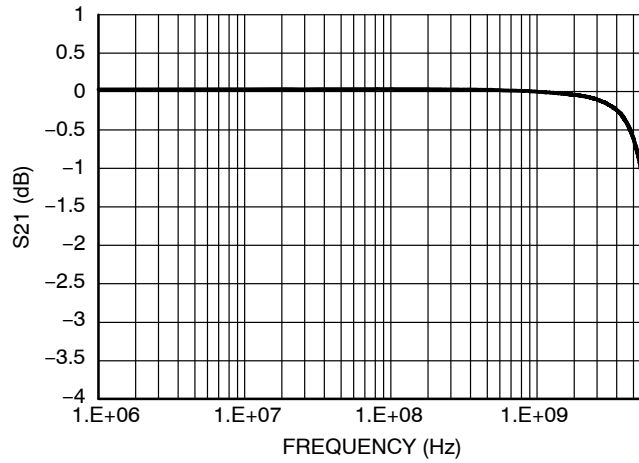
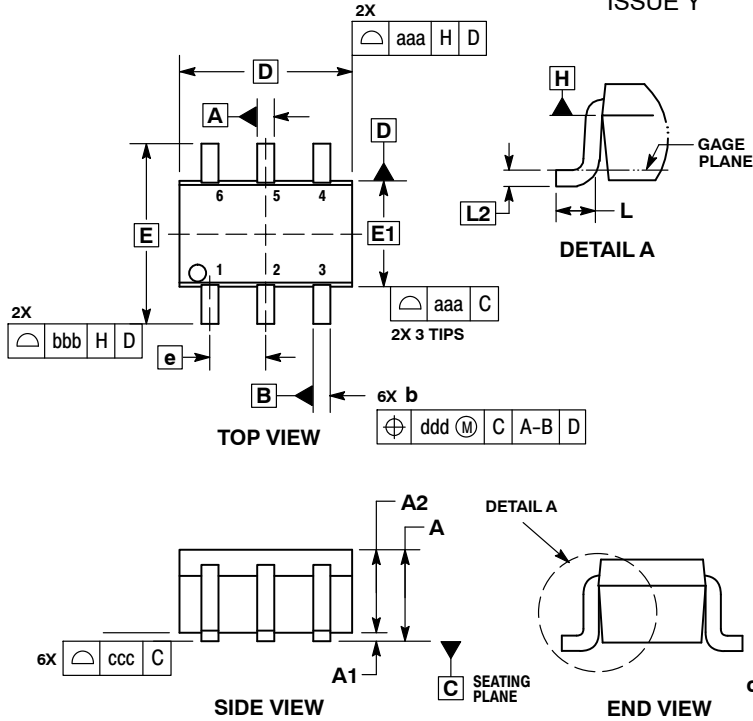


Figure 12. Typical Insertion Loss

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## PACKAGE DIMENSIONS

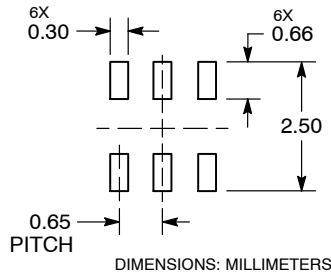
SC-88/SC70-6/SOT-363  
CASE 419B-02  
ISSUE Y



- NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  2. CONTROLLING DIMENSION: MILLIMETERS.
  3. DIMENSIONS D AND E1 DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.20 PER END.
  4. DIMENSIONS D AND E1 AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY AND DATUM H.
  5. DATUMS A AND B ARE DETERMINED AT DATUM H.
  6. DIMENSIONS b AND c APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN 0.08 AND 0.15 FROM THE TIP.
  7. DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 TOTAL IN EXCESS OF DIMENSION b AT MAXIMUM MATERIAL CONDITION. THE DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OF THE FOOT.

DIM	MILLIMETERS			INCHES		
	MIN	NOM	MAX	MIN	NOM	MAX
A	---	---	1.10	---	---	0.043
A1	0.00	---	0.10	0.000	---	0.004
A2	0.70	0.90	1.00	0.027	0.035	0.039
b	0.15	0.20	0.25	0.006	0.008	0.010
C	0.08	0.15	0.22	0.003	0.006	0.009
D	1.80	2.00	2.20	0.070	0.078	0.086
E	2.00	2.10	2.20	0.078	0.082	0.086
E1	1.15	1.25	1.35	0.045	0.049	0.053
e	0.65 BSC			0.026 BSC		
L	0.26	0.36	0.46	0.010	0.014	0.018
L2	0.15 BSC			0.006 BSC		
aaa	0.15			0.006		
bbb	0.30			0.012		
ccc	0.10			0.004		
ddd	0.10			0.004		

### RECOMMENDED SOLDERING FOOTPRINT\*



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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